Qualification Test Report 501-115002 Rev.A **Product Specification** 108-115001 Date 2Jun2010 THIS INFORMATION IS CONFIDENTIAL AND IS DISCLOSED TO YOU ON CONDITION THAT NO FURTHER DISCLOSURE IS MADE BY YOU TO OTHER THAN AMP PERSONNEL WITHOUT WRITTEN AUTHORIZATION FROM AMP SHANGHALLID **Prepared by** Francis Lee **≢**_{Tyco} **Tyco Electronics** Reviewed by Shanghai Ltd Électronics Martin Li LOC Approved by 501-115002 Steven Yao TITLE **PAGE** 2Jun USB 3.0 Plug & Receptacle F.L **Initial release** 2010 1 of 9 REVISION RECORD DR DATE

1. Introduction

1.1 Objective

Testing was performed on the USB Consortium, Plug & Receptacle Lead Free Version connectors to determine if it meets the requirements of Design Objective, 108-115001, Rev. A.

1.2 Scope

This report covers the electrical, mechanical and environmental performance requirements of the USB Consortium, Plug & Receptacle Lead Free Version connectors.

1.3 Conclusion

The USB Consortium, Plug & Receptacle Lead Free Version connectors listed in paragraph 1.5, meets the electrical, mechanical and environmental performance requirements of Product Specification, 108-115001, Rev. A.

1.4 Product Description

The USB Consortium Plug & Receptacle Lead Free Version connectors are cable mounted plugs and printed circuit mounted receptacles. The contacts are made of a copper alloy with gold over palladium nickel plating in contact area, tin plating on solder area all over nickel plating. The housing material is thermoplastic UL94V-0 rated.

1.5 Test Samples

The test samples were representative of normal production lots, and samples identified with the following part numbers were used for test:

Test Group	Quantity	Part Number	Description
1,2,3,4,5,6,7,8.9.	5 ea.		Cable Assembly
1,2,3,4,5,6,7,8.9.	5 ea.		Receptacle Assembly

1.6 Environmental Conditions

Unless otherwise stated, the following environmental conditions prevailed during test:

Temperature: 15°C to 35°C Relative Humidity: 20 to 80%

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2. Test Method Test requirement and Procedures summary

Para.	,	Test Items	Requir	rements		Procedures			
2.1	Examinati	on of Product	Meets requireme drawing	•		Visual inspection No physical damage			
			Electrical Re	quiremen	ts				
2.2	Low level	Low level contact resistance $ \begin{array}{c} 30 \text{ m}\Omega \text{ Max initial for VBUS and} \\ \text{GND contacts (pin1, pin4, pin7)} \\ 50 \text{ m}\Omega \text{ Max. initial for all other} \\ \text{contacts(pin2, pin3,} \\ \text{pin5,pin6,pin8, pin9)} \\ \text{Maximum change (delta) of +10m} \\ \Omega \text{ after environmental stresses} \\ \end{array} $			EIA 364-23 Subject mated contacts asser housing to 20 mV Max. ope at 10 mA				
2.3	Dielectric voltage	withstanding	No creeping disc flashover shall or	harge nor	EIA 364-20 0.1k VAC for 1 minute. Cur leakage: 5 mA Max. Test between adjacent conta unmated and mated connect	icts of			
2.4	Insulation	Resistance	A minimum of 1 resistance	00 Μ Ω in	sulation	EIA 364-21 Test between adjacent conta unmated and mated connect			
2.5	Contact C	urrent Rating	The current is ap contacts, the delt shall not exceed point on the USE under test, when ambient tempera	a tempera +30°C at a 3.0 connumeration	any actors at an	EIA 364-70,Method 2 A current of 1.8A shall be applied to VBUS pin and its corresponding GND pin (pin1, pin4, pin7]. Additionally, a minimum current of 0.25A shall be applied to all the other contacts (pin2, pin, pin5, pin6, pin8, pin9)			
	<u> </u>		Mechanical R	equireme	nts	(pin2, pin, pine, pine, pine,	pm)		
2.6	Durability	,	No physical dama	ge to any	part of th	EIA-364-09			
2.0	Durability		Connectors and the shall Occur.			Mate and unmate samples for 1500 cycles at maximum rate of 200 cycles per hour			
2.7	Vibration		No electrical discontinuities greater than 1 microsecond shall occur. No evidence of physical damage. See Note No electrical discontinuity greater that 1 microsecond shall occur.			EIA-364-28,test condition VII ,test condition letter D, Subject mated connectors.15 minutes in each of 3 mutually perpendicular planes.			
2.8	Physical S	Shock							
2.9	Mating Fo	orce	35N maximum			EIA-364-13 ,Method A Measure force necessary to mate samples at maximum rate of 12.5mm a minute.			
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Para.	Test Items	Requirements		Procedures				
2.10	Unmating Force	10N minimum initial and 8N after the specified mate / unmate or durability		EIA-364-13 ,Method A Measure force necessary to unmate sam maximum rate of 12.5mm per minute.	ples at			
2.11	Solder ability	Solderable area shall have minimum osolder coverage		EIA-364-52 Subject surface mount samples to solder				
2.12	Reseating	No evidence of physical damage		Manually unplug/plug the connector .Pe such cycles	erform 3			
2.13	Cable Flexing	No physical damage or discontinuity of 1 ms	scontinuity over EIA 364-41 ,Condition I during flexing shall occur to the cable a with Dimension X=3.7 times the cable and 100 cycles in each of two planes					
2.14	Cable Pull- Out	No physical damage to the cable assenshall occur		y EIA 364-38 Condition A Its subjected to a 40N axial load for minimum of 1 minute while clamping one of the cable plug				
		Environmental R	Require	ements				
2.15	Thermal Shock	30 mΩ Max initial for VBUS and GN contacts (pin1 ,pin4 ,pin7) 50 mΩ Max. initial for all other contacts,(pin2,pin3,pin5,pin6,pin8,pin Maximum change (delta) of +10m Ω a environmental stresses	in 4 ,pin 7) Subject mated samples to 25 cycles between 13,pin 5,pin 6,pin 8,pin 9) (delta) of $+10$ m Ω after					
2.16	Temperatu re Life	30 mΩ Max initial for VBUS and GN contacts (pin1 ,pin4 ,pin7) 50 mΩ Max. initial for all other contacts,(pin2,pin3,pin5,pin6,pin8,pin Maximum change (delta) of +10m Ω a environmental stresses	n9)	Subject mated samples to temperature life at 105 °C for 120 hours				
2.17	Cyclic temperatur e & humidity	30 mΩ Max initial for VBUS and GN contacts (pin1 ,pin4 ,pin7) 50 mΩ Max. initial for all other contacts,(pin2,pin3,pin5,pin6,pin8,pin Maximum change (delta) of +10m Ω a environmental stresses	n9) after	Subject samples to between $25^{\circ}\text{C} \pm 3^{\circ}\text{C}$ at 80 3% RH and $65^{\circ}\text{C} \pm 3^{\circ}\text{C}$ at $50\% \pm 3\%$ RH, ra times should be 0.1 hour. And dwell times sl be 1.0 hour.dwell times start when the temperature and humidity have stabilized wi				
2.18	Thermal disturbance	30 mΩ Max initial for VBUS and GN contacts (pin1 ,pin4 ,pin7) 50 mΩ Max. initial for all other contacts,(pin2,pin3,pin5,pin6,pin8,pin Maximum change (delta) of +10m Ω a environmental stresses	n9)	the specified levels. Perform 24 such cycles Cycle samples to between $15^{\circ}\text{C} \pm 3^{\circ}\text{C}$ and 85°C $\pm 3^{\circ}\text{C}$, as measured on the part ramps should be a minimum of 2°C per minute, And dwell times should insure that the contacts reach the temperature extremes (a minimum of 5 minutes). Humidity is not controlled .perform 10 such cycles.				
2.19	Thermal Cycling	30 mΩ Max initial for VBUS and GN contacts (pin1 ,pin4 ,pin7) 50 mΩ Max. initial for all other contacts,(pin2,pin3,pin5,pin6,pin8,pin Maximum change (delta) of +10m Ω a environmental stresses	n9)	Cycle samples to between $15^{\circ}\text{C} \pm 3^{\circ}\text{C}$ at $\pm 3^{\circ}\text{C}$, as measured on the part.ramps sh minimum of 2°C per minute,. And dwell should insure that the contacts reach the temperature extremes (a minimum of 5 Humidity is not controlled .perform 500 cycles.	nould be limes minutes).			
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2.20	Mixed	30 mΩ Max initial for VBUS and GND	EIA 364-65 ,class IIA
	flowing	contacts (pin1 ,pin4 ,pin7)	Subject samples to environmental, class IIA for
	gas	$50 \text{ m}\Omega$ Max. initial for all other	14 days. Final LLCR should be measured after 1
		contacts,(pin2,pin3,pin5,pin6,pin8,pin9)	hour from the end of test, Detail request see
		Maximum change (delta) of $+10$ m Ω after	NOTE
		environmental stresses	

3. Qualifications Test Sequence

	Test Group											
Test of Examination	1	2	3	4	5	6	7	8	9			
				Test	Sequence			ı				
Examination of Product	1,12	1,10	1,9	1	1,10	1,3	1,7	1,5	1,3			
Low level contact resistance	2,7,9	2,5,7,9	2,5,8	2,5,7,9	2,5,7,9		3,5					
Dielectric Withstanding Voltage							2,6					
Insulation Resistance								2				
Contact current rating						2						
Durability	5	3(a)	3(a)	3(a)	3(a)		4					
Vibration			6									
Physical Shock			7									
Mating force	3,10											
Unmating force	4,11											
Solder ability									2			
Reseating	8	8		8	8							
Cable flexing								3				
Cable Pull-Out								4				
Thermal Shock		4										
Temperature Life	6		4(b)	4(b)	4(b)							
Cyclic Temperature &Humidity		6										
Thermal Disturbance				8								
Thermal Cycliing					6							
Mixed Flowing Gas				6								

NOTE

(a) Proconditioning 5 cycles

(b) Proconditioning $105\,^{\circ}\text{C}$ for 72 hours

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4 Test Result:

Group	Test Item	N Condition			Test Res	ult	Dagwinamant	Judgmen
Group			Condition	Max	Min	Ave	Requirement	Juagmen
	Examination of Product	5	Initial	No physi	cal damage	e occurred	No abnormalities	Pass
	LLCR(Pin1,4,7)	5	Initial	12.96	6.94	8.44	<30m Ω	Pass
	LLCR(Pin2,3,5,6,8,9)	3	Illitiai	13.56	10.11	11.89	<50m Ω	F 488
	Mating Force	5	Final	15.69	12.16	13.77	<35N	Pass
	Unmating Force	5	Final	22.06	19.53	21.14	>10N	Pass
	Durability	5	Final	No physi	cal damage	e occurred	No abnormalities	Pass
1	Temperature Life		Final	Pastern c	ome out fr	om the plug	No abnormalities	Pass
	LLCR (△R)	5	5 Final	8.06	-1.58	2.79	<10 m Ω	Pass
	Reseating	5	Final	No physi	cal damag	e occurred	No abnormalities	Pass
	LLCR (△R)	5	Final	9.01	-0.42	4.04	<10 m Ω	Pass
	Mating Force	5	Final	17.51	9.25	12.02	<35N	Pass
	Unmating Force	5	Final	17.03	12.66	14.79	>8N	Pass
	Examination of Product	5	Final	Pastern c	ome out fr	om the plug	No abnormalities	Pass
	Examination of Product	5	Initial	No physi	cal damag	e occurred	No abnormalities	Pass
	LLCR(Pin1,4,7)	5	Initial	8.54	5.73	7.40	<30m Ω	Pass
	LLCR(Pin2,3,5,6,8,9)	3	Illitiai	13.62	9.83	11.51	<50m Ω	Pass
2	Durability	5	Final	No physi	cal damage	e occurred	No abnormalities	Pass
۷	Thermal Shock	5	Final	No physi	cal damag	e occurred	No abnormalities	Pass
	LLCR (△R)	△R) 5		3.97	-3.57	0.13	<10 m Ω	Pass
	Cyclic Temperature Humidity		Final	No physi	cal damag	e occurred	No abnormalities	Pass
	LLCR (△R)	5	Final	3.20	-2.73	-0.03	<10 m Ω	Pass

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Group	Test Item	N	Condition		Test Resi	ult	Requirement	Judgmen
Group			Condition	Max	Min	Ave	Requirement	Juagmen
	Reseating	5	Final	No physic	cal damage	e occurred	No abnormalities	Pass
	LLCR (△R)	5	Final	2.79	-2.22	0.01	<10 m Ω	Pass
	Examination of Product	5	Final	No physic	cal damage	e occurred	No abnormalities	Pass
	Examination of Product	5	Initial	No physic	cal damage	No abnormalities	Pass	
	LLCR(Pin1,4,7)	5	Initial	7.91	5.94	6.74	<30m Ω	Pass
	LLCR(Pin2,3,5,6,8,9)		Illitiai	12.32	9.53	10.85	<50m Ω	1 455
	Durability	5	Final	No physical damage occurred			No abnormalities	Pass
	Temperature Life	5	Final	No physical damage occurred		No abnormalities	Pass	
3	LLCR (\triangle R)	5	Final	8.08	-0.51	2.66	<10 m Ω	Pass
	Vibration	5	Final	No discontinuities of 1 microsecond or longer duration occurred			No abnormalities	Pass
	Physical Shock	5	Final		iscontinuit ond or lon occurred	ger duration	No abnormalities	Pass
	LLCR (\triangle R)	5	Final	6.71	-0.91	2.33	<10 m Ω	Pass
	Examination of Product	5	Final	No physic	cal damage	e occurred	No abnormalities	Pass
4	Examination of Product	5	Initial	No physic	cal damage	e occurred	No abnormalities	Pass
4	LLCR(Pin1,4,7)	5	Initial	14.79	7.51	8.92	<30m Ω	Pass
	LLCR(Pin2,3,5,6,8,9)		initiai	13.48	10.38	12.11	<50m Ω	1 455
	Durability	5	Final	No physi	ical damag	e occurred-	No abnormalities	Pass

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Group	Test Item	N	Condition		Test Resu	ılt	Paguiramant	Indgaman
Group	rest item	IN	Condition	Max	Min	Ave	Requirement	Judgemen
	Temperature Life	5	Final	No phys	sical damag	ge occurred	No abnormalities	Pass
	LLCR (\triangle R)	5	Final	1.34	-2.97	-0.37	<10 m Ω	Pass
	Mix Flow Gas	5	Final	No phys	sical damag	ge occurred	No abnormalities	Pass
	LLCR (\triangle R)	5	Final	3.36	-1.23	0.46	<10 m Ω	Pass
	Thermal Disturbance	5	Final	No phys	sical damag	ge occurred	No abnormalities	Pass
	Reseating	5 Final No physical damage occurred			No abnormalities	Pass		
	LLCR (\triangle R)	5	Final	3.24	-0.84	0.71	<10 m Ω	Pass
	Examination of Product	5	Final	No phys	sical damag	ge occurred	No abnormalities	Pass
	Examination of Product	5	Initial	No phys	sical damag	ge occurred	No abnormalities	Pass
	LLCR(Pin1,4,7)	5	Initial	9.15	6.41	7.67	<30m Ω	Pass
	LLCR(Pin2,3,5,6,8,9)		lintiai	12.55	10.15	11.44	<50m Ω	
	Durability	5	Final	No phys	sical damag	ge occurred	No abnormalities	Pass
	Temperature Life	5	Initial	No phys	sical damag	ge occurred	No abnormalities	Pass
5	LLCR (\triangle R)	5	Final	3.33	-1.46	0.91	<10 m Ω	Pass
	Thermal Cycling	5	Final	No phys	sical damag	ge occurred	No abnormalities	Pass
	LLCR (\triangle R)	5	Final	4.25	-1.36	0.87	<10 m Ω	Pass
	Reseating	5	Final	No physical damage occurred		No abnormalities	Pass	
	LLCR (\triangle R)	5	Final	2.80	-0.16	0.68	<10 m Ω	Pass
	Examination of Product	5	Final	No phys	sical damag	ge occurred	No abnormalities	Pass

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Group Test Item	N	Condition	Test Result			Requirement	Judgemen	
Group	rest item	11	Condition	Max	Min	Ave	Requirement	Judgemen
	Examination of Product	5	Initial	No physi	cal damage	e occurred	No abnormalities	Pass
6	Contact Current Rating (Pin1,4,7)	5	Final	9.57	4.55	7.00	<30℃	Pass
	Contact Current Rating (Pin2,3,5,6,8,9)	3	Tinui	15.13	10.24	12.92	<30℃	1 ass
	Examination of Product	5 Final		No physical damage occurred			No abnormalities	Pass
	Examination of Product	5	Initial	No physical damage occurred			No abnormalities	Pass
	Dielectric Withstanding Voltage (mated)	5	Initial	No physi	cal damage	e occurred	No abnormalities	Pass
	Dielectric Withstanding Voltage (unmated)	5	Initial	No physi	cal damage	e occurred	No abnormalities	Pass
	LLCR(Pin1,4,7)	. 5	Initial	10.15	7.43	8.65	<30m Ω	Pass
	LLCR(Pin2,3,5,6,8,9)			13.55	11.25	12.34	<50m Ω	Pass
7	Durability	5	Final	No physi	cal damage	coccurred	No abnormalities	Pass
	LLCR $(\triangle R)$	5	Final	4.25	-1.95	0.78	<10 m Ω	Pass
	Dielectric Withstanding Voltage (mated)	5	Final	No physi	cal damage	e occurred	No abnormalities	Pass
	Dielectric Withstanding Voltage (unmated)	5	Final	No physi	cal damage	e occurred	No abnormalities	Pass
	Examination of Product	5	Final	No physi	cal damage	e occurred	No abnormalities	Pass
	Examination of Product	5	Initial	No physi	cal damage	e occurred	No abnormalities	Pass
	Insulation Resistance	5	Initial	7.30E+11	4.76E+10	1.77E+11	>100M Ω	Pass
8	Cable Flexing	5	Final	micro	e discontinosecond or ration occu	longer	No abnormalities	Pass
	Cable Pull-out	5	Initial	No performed			No abnormalities	Pass
	Examination of Product	5	Final	No physi	cal damage	e occurred	No abnormalities	Pass

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Group	Test Item	Item N		Test Result			Requirement	Judgemen
			Condition	Max	Min	Ave		
	Examination of Product	5	Initial	No physi	cal damage	coccurred	No abnormalities	Pass
9	Solderability	5	Initial	There are minimum of 95% solder coverage			No abnormalities	Pass
	Examination of Product	5	Final	No physical damage occurred			No abnormalities	Pass